

**BUILT-IN SELF TEST SYSTEM AND METHOD FOR HIGH SPEED CLOCK
AND DATA RECOVERY CIRCUIT**

Abstract of the Disclosure

5 A built-in self test system for testing a clock and
data recovery circuit is disclosed. The present invention
provides a built-in self test circuit which operates with
high speed phase lock loop. The built-in circuit comprises
data generating means for generating a test data byte and
serializing means coupled to the data generating means for
10 converting the test data byte into serial test data. The
clock and data recovery means are coupled to the output of
the serializing means for recovering the clock and test data
from the serial test data. A deserializing means coupled to
the output of the clock and data recovery means converts the
15 recovered serial test data into a recovered test data byte,
and analyzing means connected to the output of the
deserializing means compares the recovered test data byte to
the initial test data byte.